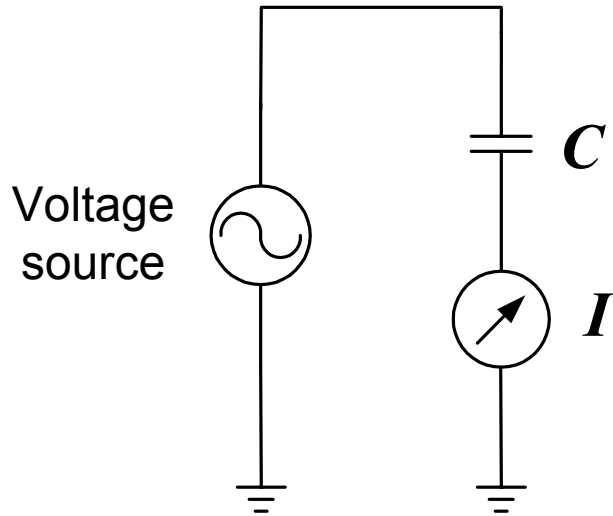


Inductance and Capacitance Measurements

■ Capacitance Measurements



$$I = \frac{V}{X_C} = V(2\pi fC)$$

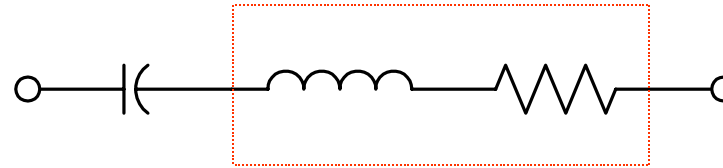
Example: $C = 10 \text{ pF}$, $V = 10 \text{ V}$ (limited by breakdown voltage of the capacitance), $I = 100 \text{ mA}$; give $f = 1600 \text{ MHz}$ → parasitic components are dominate the measurements

■ **Simple**

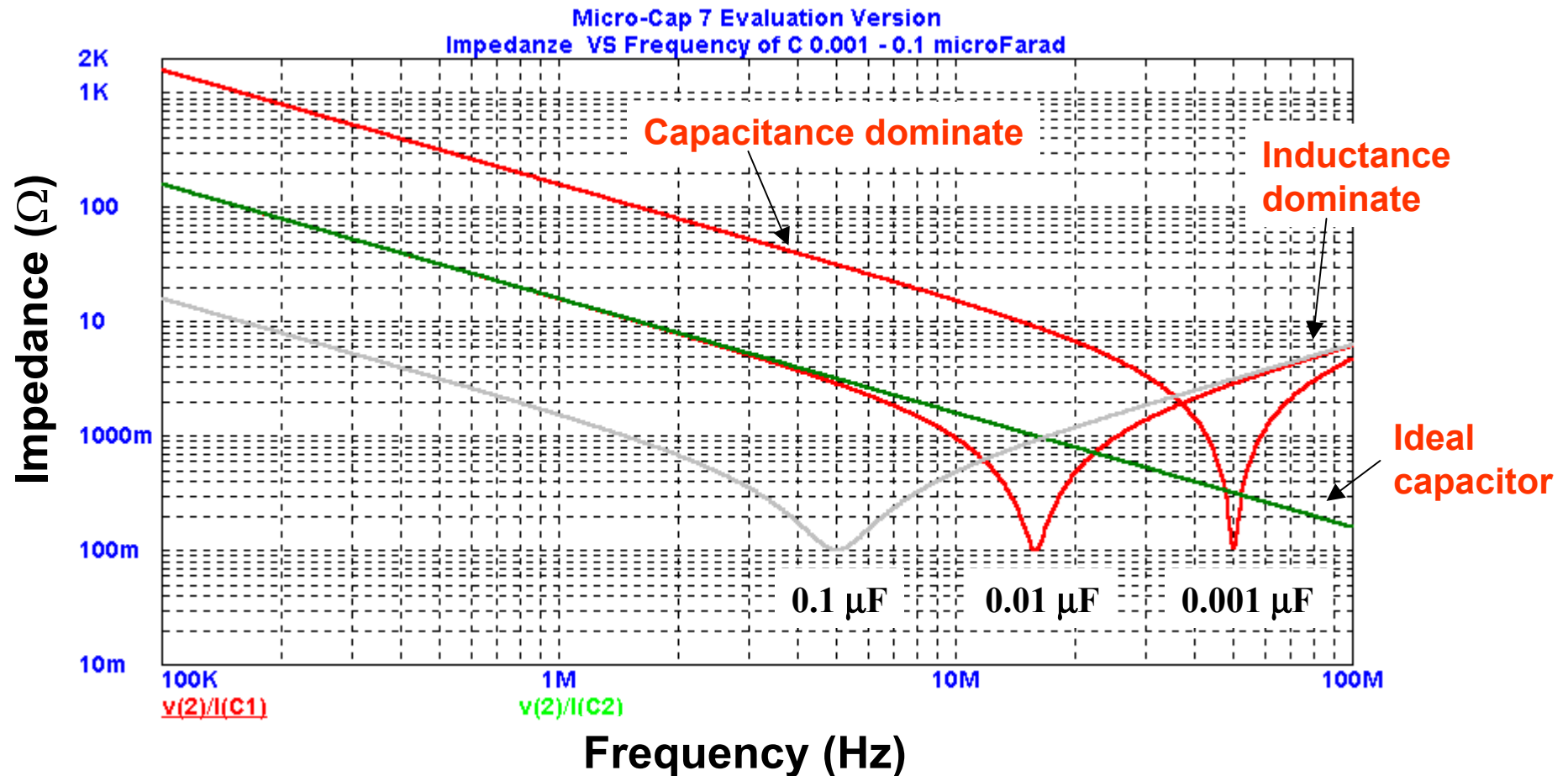
■ **Not practical in the real applications**

$$Z = R + j \left(\omega L - \frac{1}{\omega C} \right)$$

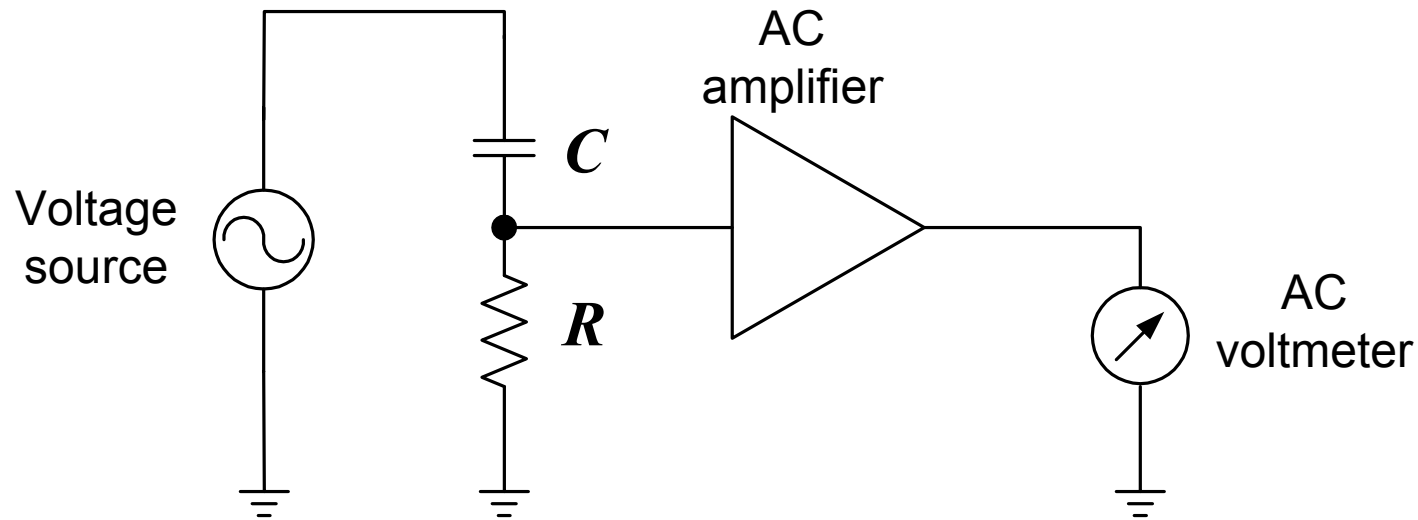
Residual components



Equivalent circuit of a capacitor at high frequency



Inductance and Capacitance Measurements

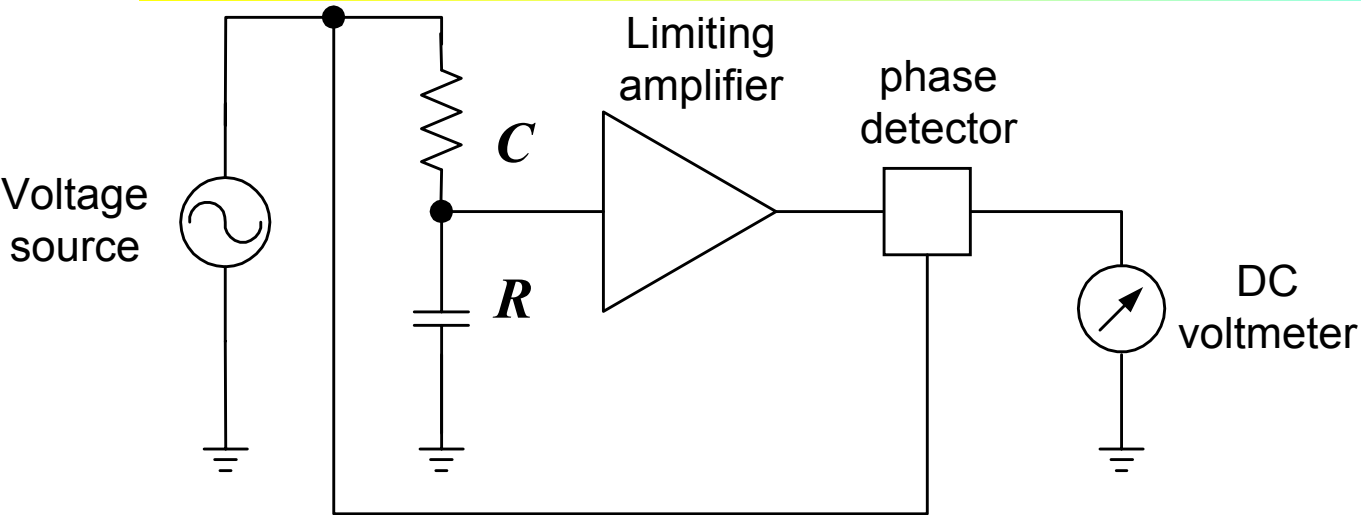


$$|V| = A \frac{RV_{in}}{\sqrt{R^2 + X_C^2}} = A \frac{RV_{in}}{\sqrt{R^2 + \left(\frac{1}{2\pi fC}\right)^2}}$$

Where A = Amplifier gain

- Non-linear relationship between V and C
- It is hard to keep the amplifier gain constant over the large input voltage

Inductance and Capacitance Measurements



■ In this scheme, we measure the phase difference between the input voltage, V_{in} and the voltage across the series resistance.

■ Here, the magnitude of the amplifier is not a critical factor, its gain should be large enough to give an output that can be detected by the phase detector.

$$\mathbf{V} = A \frac{jX_C V_{in}}{R + jX_C} = A \frac{X_C (X_C + jR) V_{in}}{R^2 + X_C^2} \quad \longrightarrow \quad \theta = \arctan\left(\frac{R}{X_C}\right) = \arctan(2\pi fRC)$$

Taylor's Series: $\theta = \arctan(2\pi fRC) = 2\pi fRC - \frac{1}{3}(2\pi fRC)^3 + \frac{1}{5}(2\pi fRC)^5 \dots$

If $2\pi fRC < 0.1$; that gives $\theta \sim 2\pi fRC$ within 0.3 % error $\longrightarrow \theta \approx 2\pi fRC$

Inductance and Capacitance Measurements

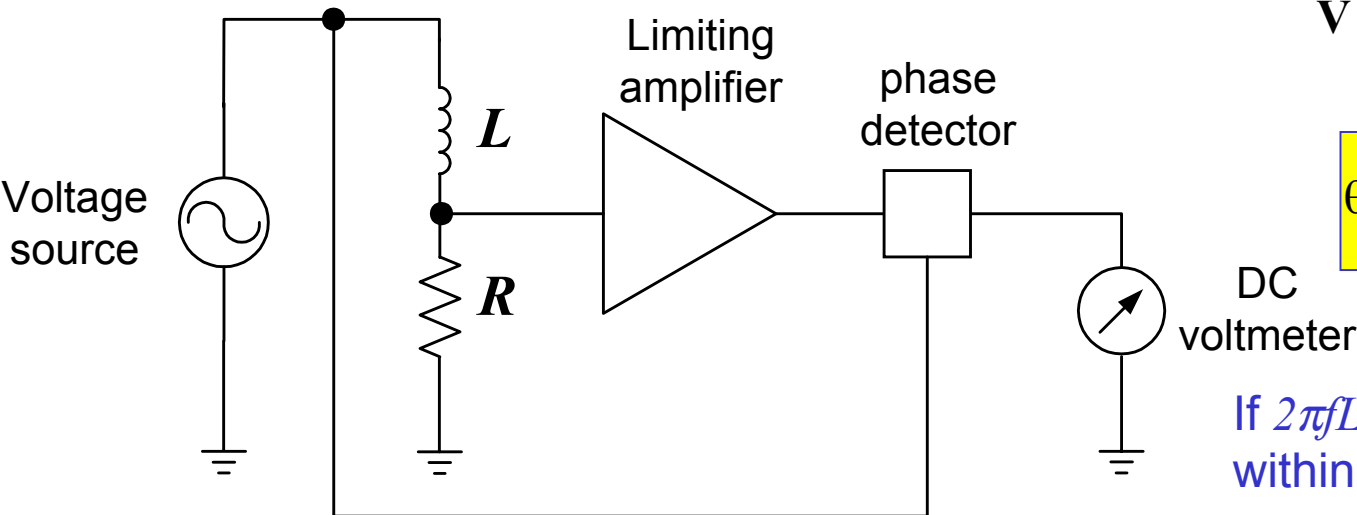
Example: to cover C from 0-100 pF with a source frequency of 1 MHz; how can we select the series resistance.

$$0.1 = 2\pi fRC = 2\pi \times 1 \text{ MHz} \times R \times 100 \text{ pF}$$

Solve for R :

$$R = \frac{0.1}{2\pi \times 10^{-4}} = 1590 \Omega$$

■ Inductance Measurements



$$V = A \frac{RV_{in}}{R + jX_L} = A \frac{R(R - jX_L)V_{in}}{R^2 + X_L^2}$$

$$\theta = \arctan\left(\frac{X_L}{R}\right) = \arctan\left(\frac{2\pi fL}{R}\right)$$

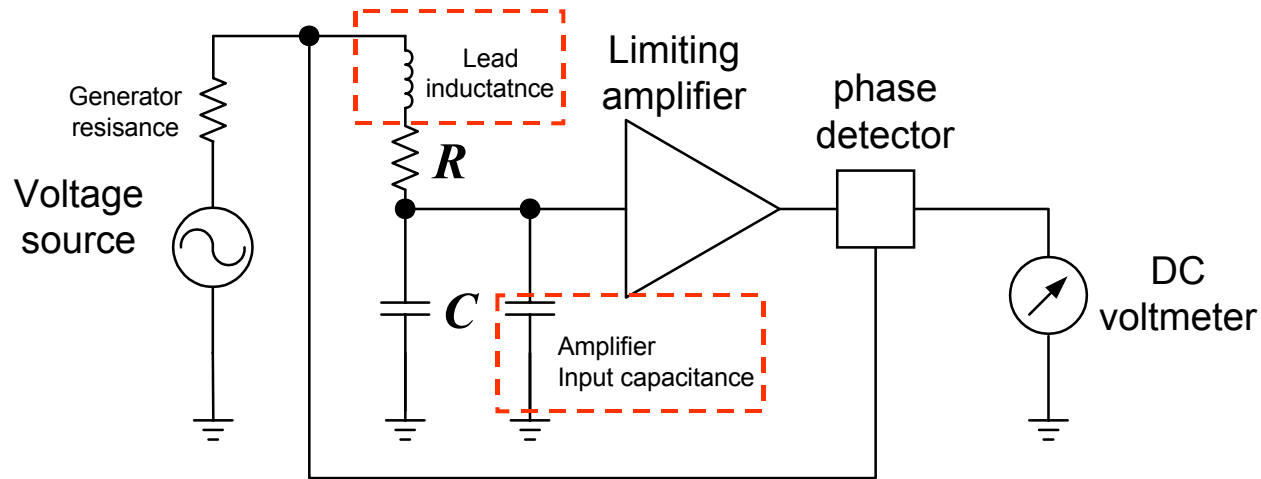
If $2\pi fL/R < 0.1$; that gives $\theta \sim 2\pi fL/R$ within 0.3 % error

$$\theta \approx 2\pi fL / R$$

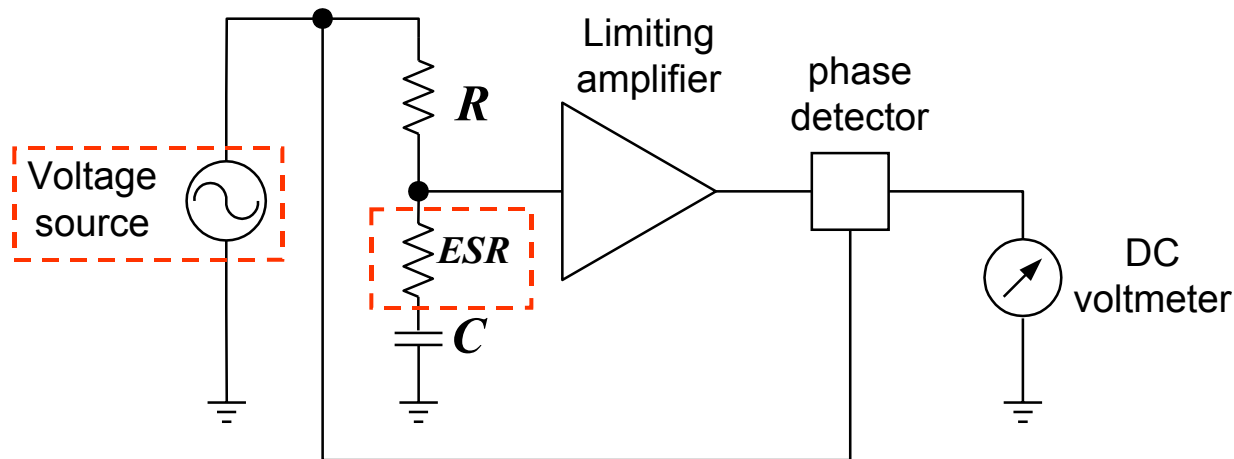
■ Example: to cover L from 0-1 μ H with a source frequency of 1 MHz; the series resistance for full scale deflection is 62.8 Ω

Source of Errors

■ Parasitic components in the instruments



■ Non-ideal characteristic of the device under test



Therefore, This type of measurement is suitable for High Q inductance and Low D capacitance

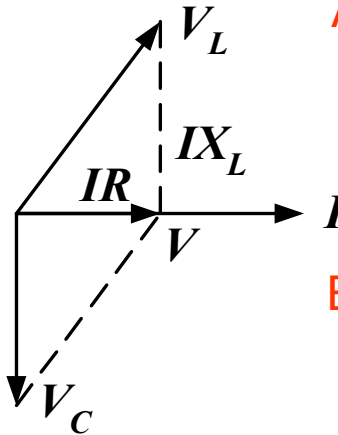
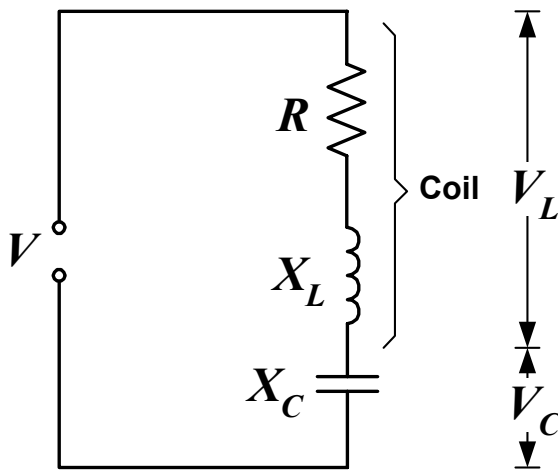
■ Harmonic distortion of the signal source

Q Meter

Q-meter is an instrument designed to measure the Q factor of a coil and for measuring inductance, capacitance, and resistance at RF.

Basic Q-meter Circuit

- The basic operation based on the well-known characteristics of series resonant circuits.



At resonance:

$$\begin{aligned}X_L &= X_C \\V_C &= V_L = IX_C = IX_L \\V &= IR\end{aligned}$$

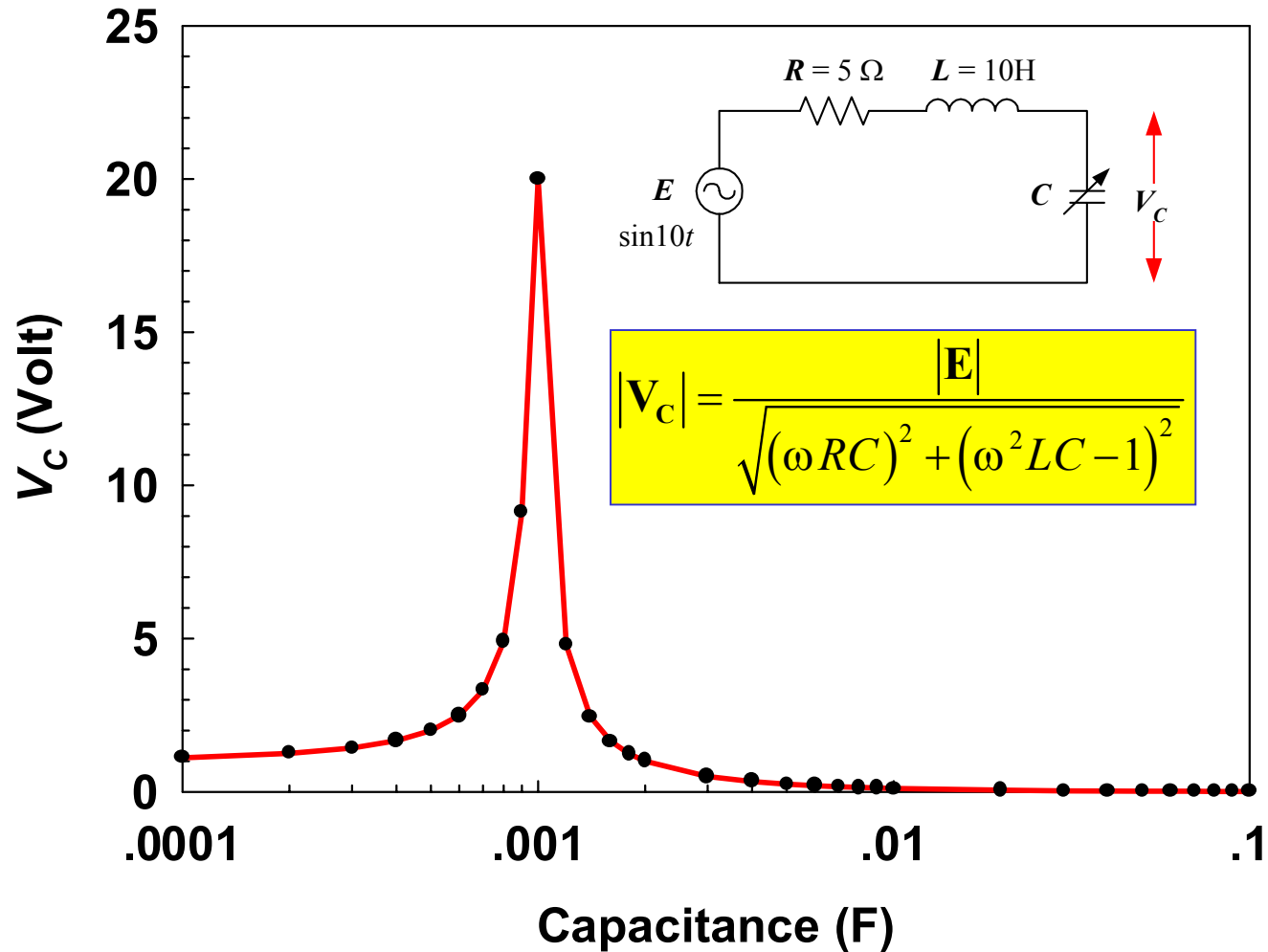
By the definition of Q :

$$Q = \frac{X_L}{R} = \frac{X_C}{R} = \frac{V_C}{V}$$

Series resonant circuit

Therefore, if V is a known constant, a voltmeter connected across the capacitor can be calibrated in term of the circuit Q

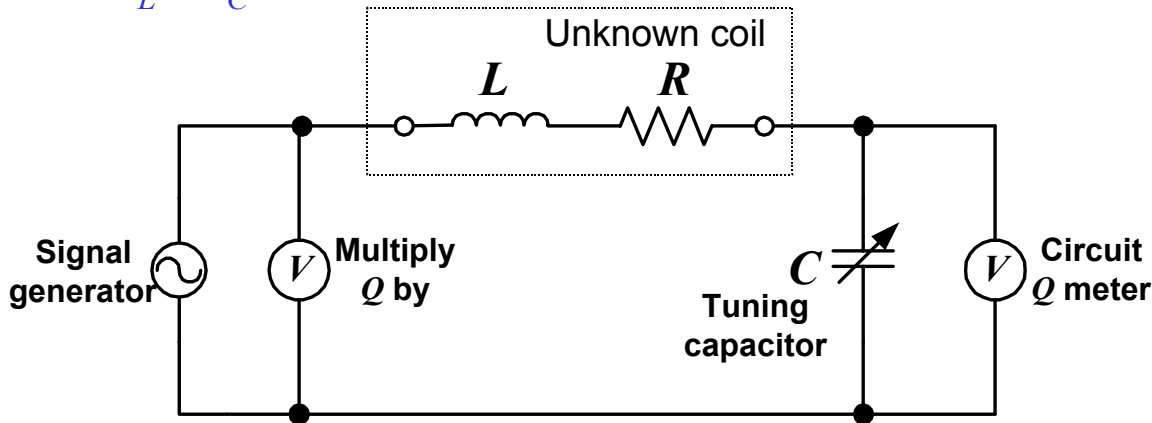
Q Meter



Q Meter

Example: when the below circuit is in the resonance, $V = 100 \text{ mV}$, $R = 5 \Omega$, and $X_L = X_C = 100 \Omega$

- (a) Calculate the coil Q and the voltmeter indication.
 (b) Determine the Q factor and voltmeter indication for another coil that $R = 10 \Omega$, and $X_L = X_C = 100 \Omega$ at resonance



Solution (a) $I = \frac{V}{R} = \frac{100 \text{ mV}}{5 \Omega} = 20 \text{ mA}$

$$V_L = V_C = IX_C = 20 \text{ mA} \times 100 \Omega = 2 \text{ V}$$

$$Q = \frac{V_C}{V} = \frac{2 \text{ V}}{100 \text{ mV}} = 20$$

(b) For the second coil:

$$I = \frac{V}{R} = \frac{100 \text{ mV}}{10 \Omega} = 10 \text{ mA}$$

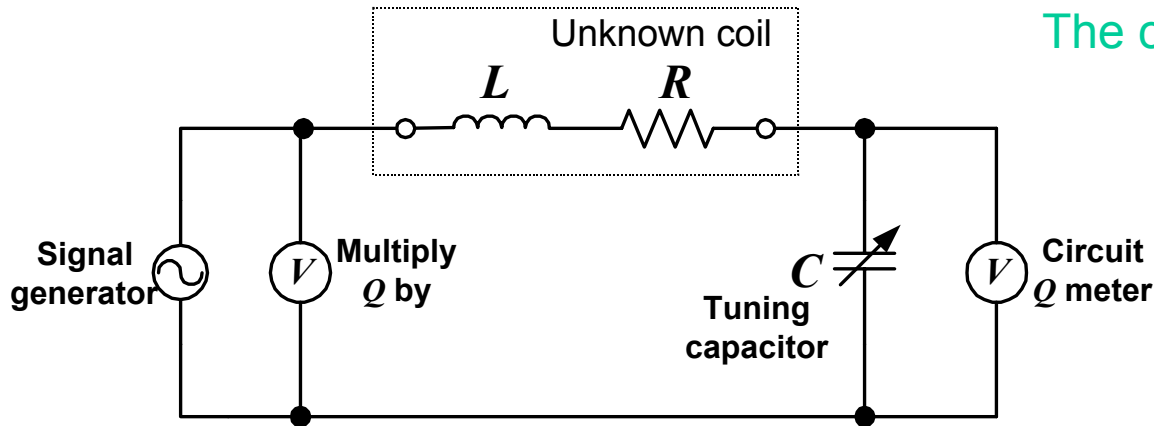
$$V_L = V_C = IX_C = 10 \text{ mA} \times 100 \Omega = 1 \text{ V}$$

$$Q = \frac{V_C}{V} = \frac{1 \text{ V}}{100 \text{ mV}} = 10$$

Measurement Method: Direct Connection

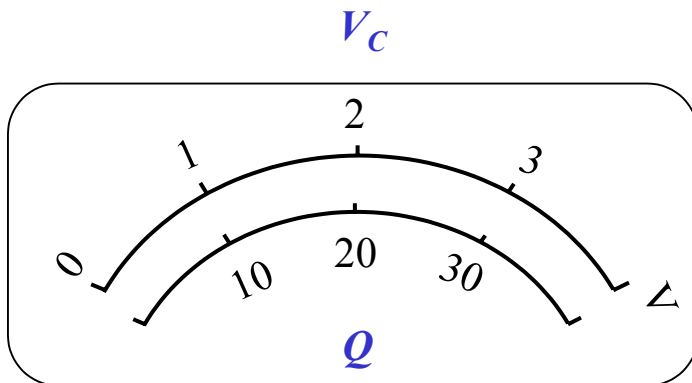
The circuit can be adjusted to the resonance by

- ✓ Preset the source frequency, and then vary the tuning capacitor
- ✓ Preset the tuning capacitor and then adjust the source frequency

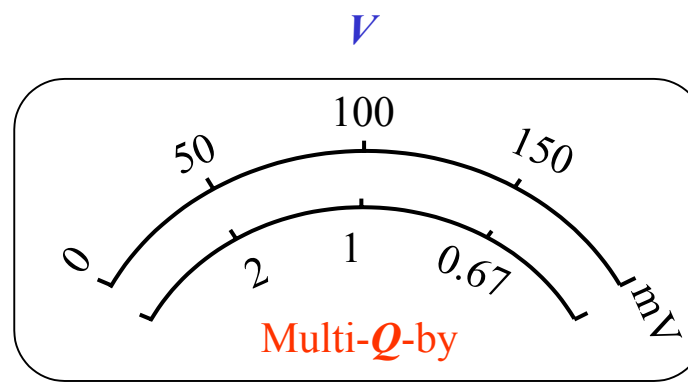


Practical Q meter:

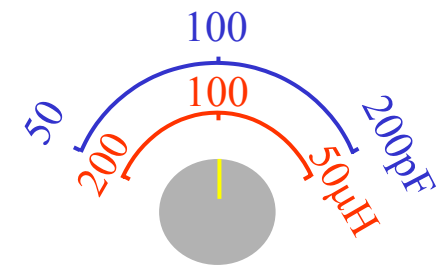
$$X_L = X_C \text{ and } L = \frac{1}{(2\pi f)^2 C} \text{ Henry}$$



(a) Capacitor voltmeter calibrated to monitor Q



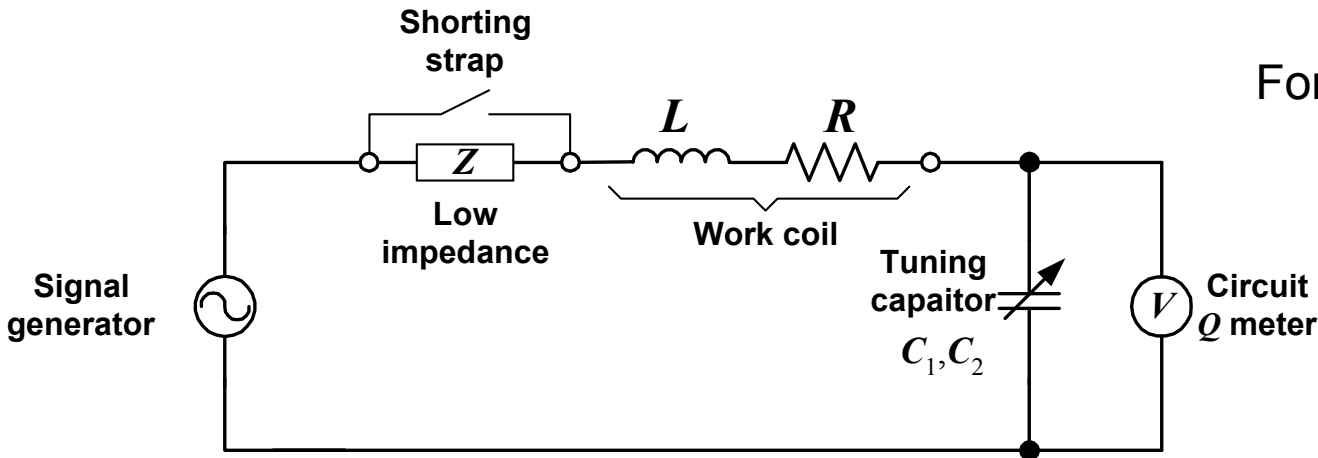
(b) Supply voltmeter calibrated as a multiply- Q -by meter



(c) Capacitance dial calibrated to indicate coil inductance

Measurement Method: Series Connection

For low-impedance components: low value resistors, small coils, and large capacitors



For the first measurement: short Z

$$X_L = X_C \text{ or } \omega L = \frac{1}{\omega C_1}$$

Thus
$$Q_1 = \frac{\omega L}{R} = \frac{1}{\omega C_1 R}$$

Q meter for a low-impedance component

For the second measurement:

The capacitor is tuned again to the new resonance point.

$$X_S = X_{C_2} - X_L \text{ or } X_S = \frac{1}{\omega C_2} - \frac{1}{\omega C_1} \quad \longrightarrow \quad X_S = \frac{C_1 - C_2}{\omega C_1 C_2}$$

X_S is inductive if $C_1 > C_2$ and capacitive if $C_2 > C_1$

Measurement Method: Series Connection

The resistive components of the unknown impedance **Z**.

$$R_1 = \frac{X_1}{Q_1} \text{ and } R_2 = \frac{X_2}{Q_2}$$

$$R_s = R_2 - R_1 = \frac{1}{\omega C_1 Q_1} - \frac{1}{\omega C_2 Q_2} \quad \text{Thus}$$

$$R_s = R_2 - R_1 = \frac{C_1 Q_1 - C_2 Q_2}{\omega C_1 Q_1 C_2 Q_2}$$

Case I: **Z** = purely resistive, $C_1 = C_2$

$$R_s = R_2 - R_1 = \frac{Q_1 - Q_2}{\omega C_1 Q_1 Q_2} = \frac{\Delta Q}{\omega C_1 Q_1 Q_2}$$

Case II: **Z** = inductive, $C_1 > C_2$

$$L_s = \frac{C_1 - C_2}{\omega^2 C_1 C_2}$$

$$Q_s = \frac{X_s}{R_s} = \frac{(C_1 - C_2) Q_1 Q_2}{C_1 Q_1 - C_2 Q_2}$$

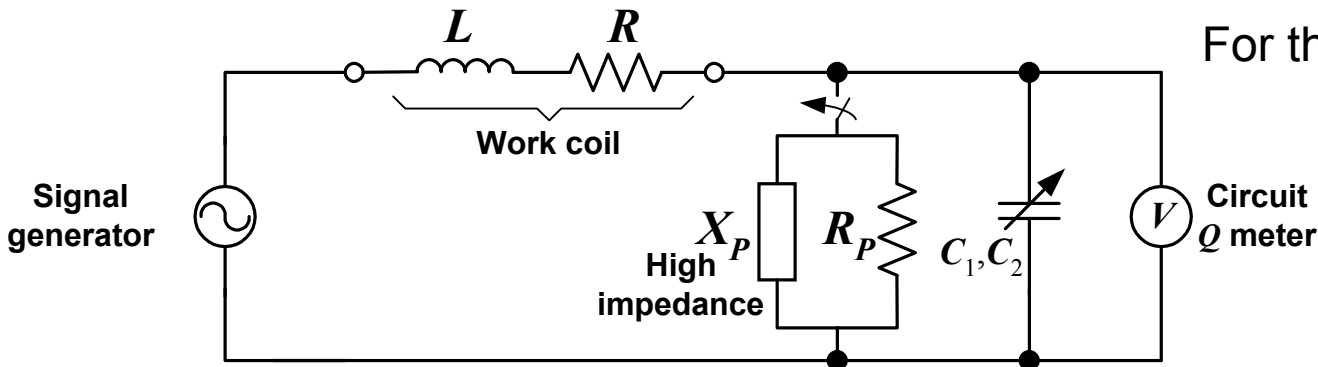
Case III: **Z** = capacitive, $C_1 < C_2$

$$C_s = \frac{C_1 C_2}{C_2 - C_1}$$

$$Q_s = \frac{X_s}{R_s} = \frac{(C_1 - C_2) Q_1 Q_2}{C_1 Q_1 - C_2 Q_2}$$

Measurement Method: Parallel Connection

For high-impedance components: high value resistors, Large coils, and small capacitors



For the first measurement: open switch

$$X_L = X_C \text{ or } \omega L = \frac{1}{\omega C_1}$$

$$\text{Thus } Q_1 = \frac{\omega L}{R} = \frac{1}{\omega C_1 R}$$

Q meter for a high-impedance component

For the second measurement:

The capacitor is tuned again to the new resonance point.

$$X_L = \frac{X_{C2} X_P}{X_{C2} + X_P} \quad \longrightarrow \quad X_P = \frac{1}{\omega (C_1 - C_2)}$$

$$L_P = \frac{1}{\omega^2 (C_1 - C_2)}$$

If the unknown is inductive, $X_P = \omega L_P$;

If the unknown is capacitive, $X_P = 1/\omega C_P$;

$$C_P = C_1 - C_2$$

Measurement Method: Parallel Connection

In a parallel resonant circuit, the total resistance at resonance: $Q_2 = R_T/X_L$

While $X_2 = X_{C1}$, Therefore $R_T = Q_2 X_L = Q_2 X_{C1} = Q_2 / C_1$

$$\frac{1}{R_T} = \frac{1}{R_P} + \frac{1}{R_{LP}}$$

Where $R_{LP} = \frac{R}{R^2 + \omega^2 L^2}$

$$\frac{1}{R_P} = \frac{1}{R_T} - \frac{1}{R_{LP}} = \frac{\omega C_1}{Q_2} - \frac{R}{R^2 + \omega^2 L^2}$$

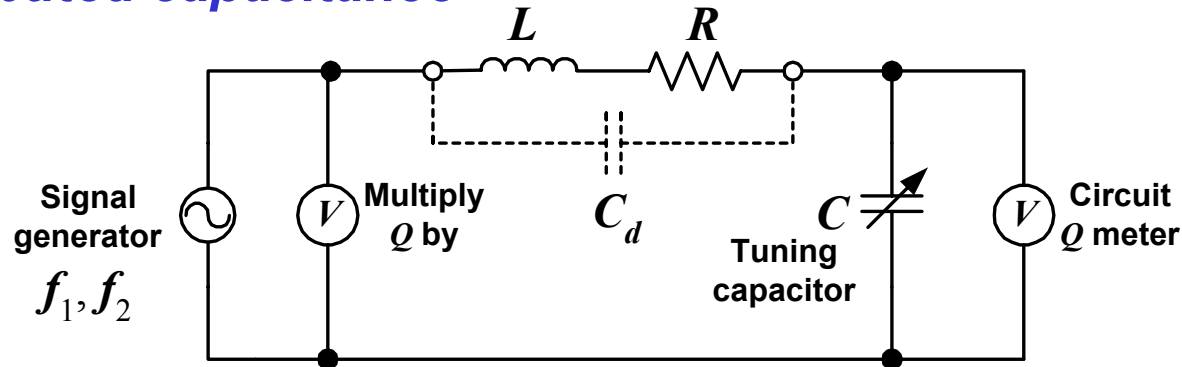
$$\frac{1}{R_P} = \frac{\omega C_1}{Q_2} - \left(\frac{1}{R} \right) \frac{1}{1 + \omega^2 L^2 / R^2} \approx \frac{\omega C_1}{Q_2} - \frac{1}{R Q_1^2}$$

since $Q_1 = 1/\omega C_1 R$ $\frac{1}{R_P} = \frac{\omega C_1}{Q_2} - \frac{\omega C_1}{Q_1} \quad R_P = \frac{Q_1 Q_2}{\omega C_1 (Q_1 - Q_2)} = \frac{Q_1 Q_2}{\omega C_1 \Delta Q}$

$$Q_P = \frac{R_P}{X_P} = \frac{(C_1 - C_2) Q_1 Q_2}{C_1 (Q_1 - Q_2)} = \frac{(C_1 - C_2) Q_1 Q_2}{C_1 \Delta Q}$$

Source of Error

■ Distributed capacitance



One simple method of finding the distributed capacitance (C_d) is to make two measurements at different frequencies

$$f = \frac{1}{2\pi\sqrt{LC}}$$

At first measurement: f_1

$$f_1 = \frac{1}{2\pi\sqrt{L(C_1 + C_d)}}$$

At first measurement: f_2

$$f_2 = \frac{1}{2\pi\sqrt{L(C_2 + C_d)}}$$

If we set $f_2 = 2f_1$

$$\frac{1}{2\pi\sqrt{L(C_2 + C_d)}} = \frac{2}{2\pi\sqrt{L(C_1 + C_d)}} \quad \longrightarrow \quad C_d = \frac{C_1 - 4C_2}{3}$$

Source of Error

The effective Q of a coil with distributed capacitance is less than the true Q

$$\text{True } Q = Q_e \left(\frac{C + C_d}{C} \right)$$

- **Residual or insertion resistance:** in the Q meter circuit can be an important source of error when the signal generator voltage is not metered.

If R_s is the source resistance, the circuit current resonance is

$$I = \frac{V}{R + R_s} \quad \text{Instead of} \quad I = \frac{V}{R}$$

Also, the indicated Q factor of the coil is

$$Q = \frac{\omega L}{R + R_s}$$

Instead of the actual coil Q , which is

$$Q = \frac{\omega L}{R}$$

Thus R_s must be kept minimized.

Source of Error

Example The self-capacitance of a coil is to be measured by using the procedure just outlined. The first measurement is at $f_1 = 2$ MHz, and $C_1 = 460$ pF. The second measurement, at $f_2 = 4$ MHz, yields a new value of tuning capacitor, $C_2 = 100$ pF. Find the distributed capacitance, C_d .

Solution

$$C_d = \frac{C_1 - 4C_2}{3} = \frac{460 - 4 \times 100}{3} = 20 \text{ pF}$$

Example A coil with a resistance of 10Ω is connected in the “direction-measurement” mode. Resonance occurs when the oscillator frequency is 1.0 MHz, and the resonating capacitor is set at 65 pF. Calculate the percentage error in the calculated value of Q by the 0.02Ω insertion resistance.

Solution The effective Q of the coil equals

$$Q_e = \frac{1}{\omega CR} = \frac{1}{2\pi \times 10^6 \times 65 \times 10^{-12} \times 10} = 245$$

The indicated Q of the coil equals

$$Q_e = \frac{1}{\omega C(R + 0.02)} = 244.5$$

The percentage error is then

$$\frac{245 - 244.5}{245} \times 100\% = 0.2\%$$